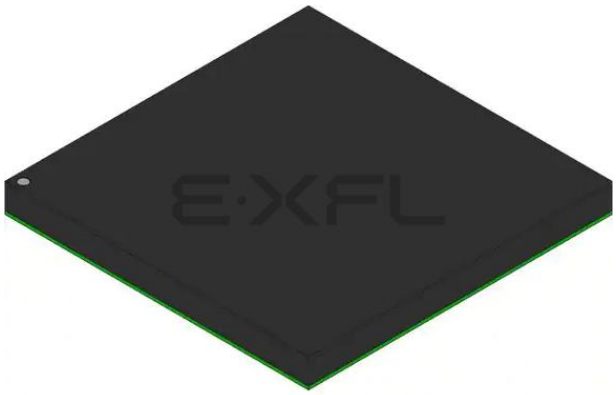

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

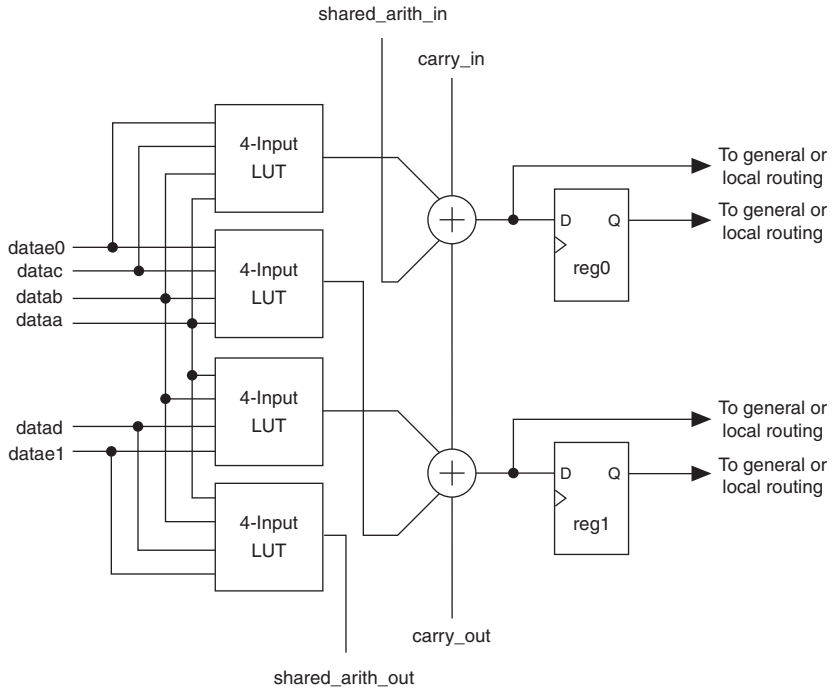
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	8970
Number of Logic Elements/Cells	179400
Total RAM Bits	9383040
Number of I/O	742
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1020-BBGA, FCBGA
Supplier Device Package	1020-FBGA (33x33)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=ep2s180f1020c3n

Figure 2–13. ALM in Shared Arithmetic Mode



Note to Figure 2–13:
(1) Inputs `dataf0` and `dataf1` are available for register packing in shared arithmetic mode.

Adder trees can be found in many different applications. For example, the summation of the partial products in a logic-based multiplier can be implemented in a tree structure. Another example is a correlator function that can use a large adder tree to sum filtered data samples in a given time frame to recover or to de-spread data which was transmitted utilizing spread spectrum technology.

An example of a three-bit add operation utilizing the shared arithmetic mode is shown in Figure 2–14. The partial sum `(S[2..0])` and the partial carry `(C[2..0])` is obtained using the LUTs, while the result `(R[2..0])` is computed using the dedicated adders.

Table 2–3. TriMatrix Memory Features (Part 2 of 2)

Memory Feature	M512 RAM Block (32 × 18 Bits)	M4K RAM Block (128 × 36 Bits)	M-RAM Block (4K × 144 Bits)
Simple dual-port memory mixed width support	✓	✓	✓
True dual-port memory mixed width support		✓	✓
Power-up conditions	Outputs cleared	Outputs cleared	Outputs unknown
Register clears	Output registers	Output registers	Output registers
Mixed-port read-during-write	Unknown output/old data	Unknown output/old data	Unknown output
Configurations	512 × 1 256 × 2 128 × 4 64 × 8 64 × 9 32 × 16 32 × 18	4K × 1 2K × 2 1K × 4 512 × 8 512 × 9 256 × 16 256 × 18 128 × 32 128 × 36	64K × 8 64K × 9 32K × 16 32K × 18 16K × 32 16K × 36 8K × 64 8K × 72 4K × 128 4K × 144

Notes to Table 2–3:

(1) The M-RAM block does not support memory initializations. However, the M-RAM block can emulate a ROM function using a dual-port RAM bock. The Stratix II device must write to the dual-port memory once and then disable the write-enable ports afterwards.

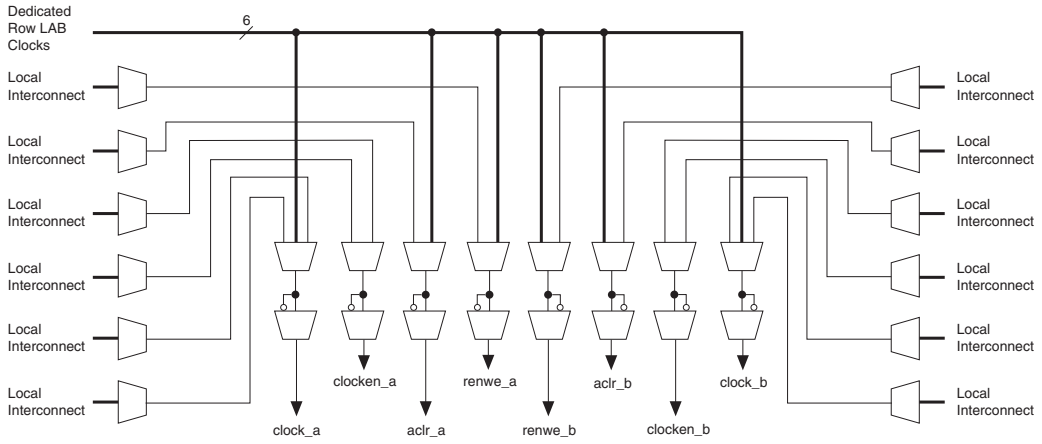
Memory Block Size

TriMatrix memory provides three different memory sizes for efficient application support. The Quartus II software automatically partitions the user-defined memory into the embedded memory blocks using the most efficient size combinations. You can also manually assign the memory to a specific block size or a mixture of block sizes.

When applied to input registers, the asynchronous clear signal for the TriMatrix embedded memory immediately clears the input registers. However, the output of the memory block does not show the effects until the next clock edge. When applied to output registers, the asynchronous clear signal clears the output registers and the effects are seen immediately.

Similar to all RAM blocks, M-RAM blocks can have different clocks on their inputs and outputs. Either of the two clocks feeding the block can clock M-RAM block registers (renwe, address, byte enable, datain, and output registers). The output register can be bypassed. The six `labclk` signals or local interconnect can drive the control signals for the A and B ports of the M-RAM block. ALMs can also control the `clock_a`, `clock_b`, `renwe_a`, `renwe_b`, `clr_a`, `clr_b`, `clocken_a`, and `clocken_b` signals as shown in Figure 2–23.

Figure 2–23. M-RAM Block Control Signals



The R4, R24, C4, and direct link interconnects from adjacent LABs on either the right or left side drive the M-RAM block local interconnect. Up to 16 direct link input connections to the M-RAM block are possible from the left adjacent LABs and another 16 possible from the right adjacent LAB. M-RAM block outputs can also connect to left and right LABs through direct link interconnect. Figure 2–24 shows an example floorplan for the EP2S130 device and the location of the M-RAM interfaces. Figures 2–25 and 2–26 show the interface between the M-RAM block and the logic array.

Table 2–5 shows the number of DSP blocks in each Stratix II device.

Table 2–5. DSP Blocks in Stratix II Devices *Note (1)*

Device	DSP Blocks	Total 9 × 9 Multipliers	Total 18 × 18 Multipliers	Total 36 × 36 Multipliers
EP2S15	12	96	48	12
EP2S30	16	128	64	16
EP2S60	36	288	144	36
EP2S90	48	384	192	48
EP2S130	63	504	252	63
EP2S180	96	768	384	96

Note to Table 2–5:

(1) Each device has either the numbers of 9 × 9-, 18 × 18-, or 36 × 36-bit multipliers shown. The total number of multipliers for each device is not the sum of all the multipliers.

DSP block multipliers can optionally feed an adder/subtractor or accumulator in the block depending on the configuration. This makes routing to ALMs easier, saves ALM routing resources, and increases performance, because all connections and blocks are in the DSP block. Additionally, the DSP block input registers can efficiently implement shift registers for FIR filter applications, and DSP blocks support Q1.15 format rounding and saturation.

Figure 2–28 shows the top-level diagram of the DSP block configured for 18 × 18-bit multiplier mode.

Modes of Operation

The adder, subtractor, and accumulate functions of a DSP block have four modes of operation:

- Simple multiplier
- Multiply-accumulator
- Two-multipliers adder
- Four-multipliers adder

Table 2–6 shows the different number of multipliers possible in each DSP block mode according to size. These modes allow the DSP blocks to implement numerous applications for DSP including FFTs, complex FIR, FIR, and 2D FIR filters, equalizers, IIR, correlators, matrix multiplication and many other functions. The DSP blocks also support mixed modes and mixed multiplier sizes in the same block. For example, half of one DSP block can implement one 18 × 18-bit multiplier in multiply-accumulator mode, while the other half of the DSP block implements four 9 × 9-bit multipliers in simple multiplier mode.

Table 2–6. Multiplier Size & Configurations per DSP Block

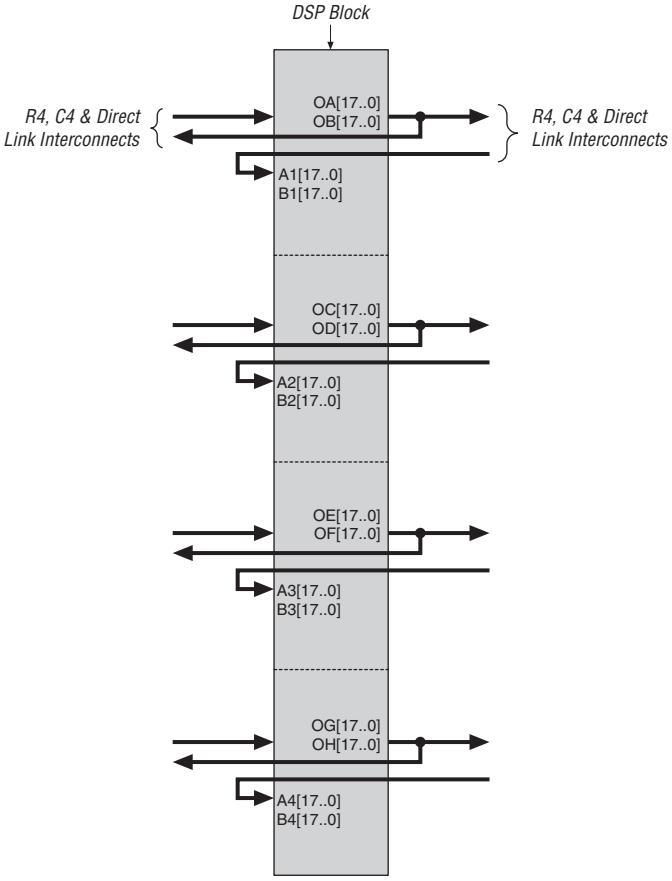
DSP Block Mode	9 × 9	18 × 18	36 × 36
Multiplier	Eight multipliers with eight product outputs	Four multipliers with four product outputs	One multiplier with one product output
Multiply-accumulator	-	Two 52-bit multiply-accumulate blocks	-
Two-multipliers adder	Four two-multiplier adder (two 9 × 9 complex multiply)	Two two-multiplier adder (one 18 × 18 complex multiply)	-
Four-multipliers adder	Two four-multiplier adder	One four-multiplier adder	-

DSP Block Interface

Stratix II device DSP block input registers can generate a shift register that can cascade down in the same DSP block column. Dedicated connections between DSP blocks provide fast connections between the shift register inputs to cascade the shift register chains. You can cascade registers within multiple DSP blocks for 9 × 9- or 18 × 18-bit FIR filters larger than four taps, with additional adder stages implemented in ALMs. If the DSP block is configured as 36 × 36 bits, the adder, subtractor, or accumulator stages are implemented in ALMs. Each DSP block can route the shift register chain out of the block to cascade multiple columns of DSP blocks.

The DSP block is divided into four block units that interface with four LAB rows on the left and right. Each block unit can be considered one complete 18 × 18-bit multiplier with 36 inputs and 36 outputs. A local interconnect region is associated with each DSP block. Like an LAB, this interconnect region can be fed with 16 direct link interconnects from the LAB to the left or right of the DSP block in the same row. R4 and C4 routing resources can access the DSP block's local interconnect region. The outputs also work similarly to LAB outputs as well. Eighteen outputs from the DSP block can drive to the left LAB through direct link interconnects and eighteen can drive to the right LAB though direct link interconnects. All 36 outputs can drive to R4 and C4 routing interconnects. Outputs can drive right- or left-column routing. Figures 2–29 and 2–30 show the DSP block interfaces to LAB rows.

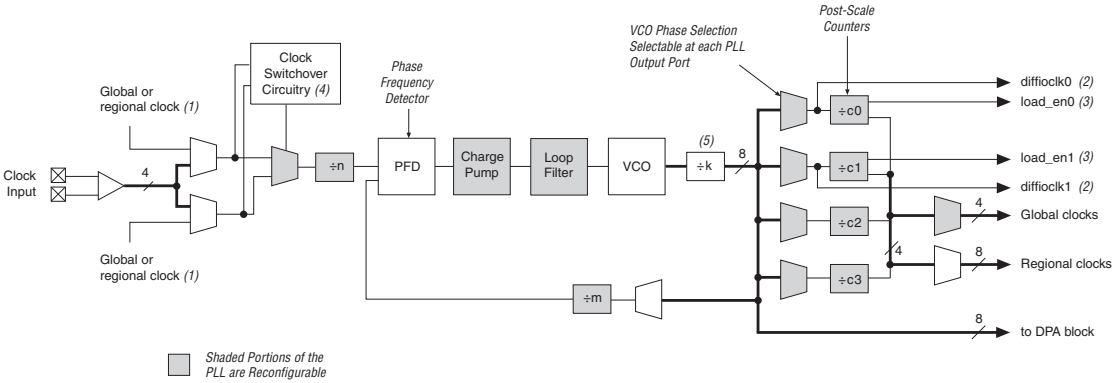
Figure 2–29. DSP Block Interconnect Interface



Fast PLLs

Stratix II devices contain up to eight fast PLLs with high-speed serial interfacing ability. Figure 2–45 shows a diagram of the fast PLL.

Figure 2–45. Stratix II Device Fast PLL *Notes (1), (2), (3)*



Notes to Figure 2–45:

(1) The global or regional clock input can be driven by an output from another PLL, a pin-driven dedicated global or regional clock, or through a clock control block, provided the clock control block is fed by an output from another PLL or a pin-driven dedicated global or regional clock. An internally generated global signal cannot drive the PLL.

(2) In high-speed differential I/O support mode, this high-speed PLL clock feeds the SERDES circuitry. Stratix II devices only support one rate of data transfer per fast PLL in high-speed differential I/O support mode.

(3) This signal is a differential I/O SERDES control signal.

(4) Stratix II fast PLLs only support manual clock switchover.

(5) If the design enables this ÷2 counter, then the device can use a VCO frequency range of 150 to 520 MHz.

See the *PLLs in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II Device Handbook* or the *Stratix II GX Device Handbook* for more information on enhanced and fast PLLs. See "High-Speed Differential I/O with DPA Support" on page 2–96 for more information on high-speed differential I/O support.

I/O Structure

The Stratix II IOEs provide many features, including:

- Dedicated differential and single-ended I/O buffers
- 3.3-V, 64-bit, 66-MHz PCI compliance
- 3.3-V, 64-bit, 133-MHz PCI-X 1.0 compliance
- Joint Test Action Group (JTAG) boundary-scan test (BST) support
- On-chip driver series termination
- On-chip parallel termination
- On-chip termination for differential standards
- Programmable pull-up during configuration

Differential On-Chip Termination

Stratix II devices support internal differential termination with a nominal resistance value of 100 Ω for LVDS or HyperTransport technology input receiver buffers. LVPECL input signals (supported on clock pins only) require an external termination resistor. Differential on-chip termination is supported across the full range of supported differential data rates as shown in the *DC & Switching Characteristics* chapter in volume 1 of the *Stratix II Device Handbook*.

For more information on differential on-chip termination, refer to the *High-Speed Differential I/O Interfaces with DPA in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II Device Handbook* or the *Stratix II GX Device Handbook*.

For more information on tolerance specifications for differential on-chip termination, refer to the *DC & Switching Characteristics* chapter in volume 1 of the *Stratix II Device Handbook*.

On-Chip Series Termination Without Calibration

Stratix II devices support driver impedance matching to provide the I/O driver with controlled output impedance that closely matches the impedance of the transmission line. As a result, reflections can be significantly reduced. Stratix II devices support on-chip series termination for single-ended I/O standards with typical R_S values of 25 and 50 Ω. Once matching impedance is selected, current drive strength is no longer selectable. Table 2–17 shows the list of output standards that support on-chip series termination without calibration.

On-Chip Series Termination with Calibration

Stratix II devices support on-chip series termination with calibration in column I/O pins in top and bottom banks. There is one calibration circuit for the top I/O banks and one circuit for the bottom I/O banks. Each on-chip series termination calibration circuit compares the total impedance of each I/O buffer to the external 25- or 50-Ω resistors connected to the `RUP` and `RDN` pins, and dynamically enables or disables the transistors until they match. Calibration occurs at the end of device configuration. Once the calibration circuit finds the correct impedance, it powers down and stops changing the characteristics of the drivers.

For more information on series on-chip termination supported by Stratix II devices, refer to the *Selectable I/O Standards in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II Device Handbook* or the *Stratix II GX Device Handbook*.

you need to support configuration input voltages of 1.8 V/1.5 V, you should set the VCCSEL to a logic high and the V_{CCIO} of the bank that contains the configuration inputs to 1.8 V/1.5 V.

For more information on multi-volt support, including information on using TDO and nCEO in multi-volt systems, refer to the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Configuration Schemes

You can load the configuration data for a Stratix II device with one of five configuration schemes (see Table 3–5), chosen on the basis of the target application. You can use a configuration device, intelligent controller, or the JTAG port to configure a Stratix II device. A configuration device can automatically configure a Stratix II device at system power-up.

You can configure multiple Stratix II devices in any of the five configuration schemes by connecting the configuration enable (nCE) and configuration enable output (nCEO) pins on each device.

Stratix II FPGAs offer the following:

- Configuration data decompression to reduce configuration file storage
- Design security using configuration data encryption to protect your designs
- Remote system upgrades for remotely updating your Stratix II designs

Table 3–5 summarizes which configuration features can be used in each configuration scheme.

Table 3–5. Stratix II Configuration Features (Part 1 of 2)

Configuration Scheme	Configuration Method	Design Security	Decompression	Remote System Upgrade
FPP	MAX II device or microprocessor and flash device	✓ *(1)*	✓ *(1)*	✓
	Enhanced configuration device		✓ *(2)*	✓
AS	Serial configuration device	✓	✓	✓ *(3)*
PS	MAX II device or microprocessor and flash device	✓	✓	✓
	Enhanced configuration device	✓	✓	✓
	Download cable *(4)*	✓	✓	

Table 3–5. Stratix II Configuration Features (Part 2 of 2)

Configuration Scheme	Configuration Method	Design Security	Decompression	Remote System Upgrade
PPA	MAX II device or microprocessor and flash device			✓
JTAG	Download cable *(4)*			
	MAX II device or microprocessor and flash device			

Notes for Table 3–5:

(1) In these modes, the host system must send a DCLK that is 4× the data rate.

(2) The enhanced configuration device decompression feature is available, while the Stratix II decompression feature is not available.

(3) Only remote update mode is supported when using the AS configuration scheme. Local update mode is not supported.

(4) The supported download cables include the Altera USB Blaster universal serial bus (USB) port download cable, MasterBlaster serial/USB communications cable, ByteBlaster II parallel port download cable, and the ByteBlasterMV parallel port download cable.

See the *Configuring Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II Device Handbook* or the *Stratix II GX Device Handbook* for more information about configuration schemes in Stratix II and Stratix II GX devices.

Device Security Using Configuration Bitstream Encryption

Stratix II FPGAs are the industry's first FPGAs with the ability to decrypt a configuration bitstream using the Advanced Encryption Standard (AES) algorithm. When using the design security feature, a 128-bit security key is stored in the Stratix II FPGA. To successfully configure a Stratix II FPGA that has the design security feature enabled, it must be configured with a configuration file that was encrypted using the same 128-bit security key. The security key can be stored in non-volatile memory inside the Stratix II device. This non-volatile memory does not require any external devices, such as a battery back-up, for storage.

Devices Can Be Driven Before Power-Up

You can drive signals into the I/O pins, dedicated input pins and dedicated clock pins of Stratix II devices before or during power-up or power-down without damaging the device. Stratix II devices support any power-up or power-down sequence (V_{CCIO}, V_{CCINT}, and V_{CCPD}) in order to simplify system level design.

I/O Pins Remain Tri-Stated During Power-Up

A device that does not support hot-socketing may interrupt system operation or cause contention by driving out before or during power-up. In a hot socketing situation, Stratix II device's output buffers are turned off during system power-up or power-down. Stratix II device also does not drive out until the device is configured and has attained proper operating conditions.

Signal Pins Do Not Drive the V_{CCIO}, V_{CCINT} or V_{CCPD} Power Supplies

Devices that do not support hot-socketing can short power supplies together when powered-up through the device signal pins. This irregular power-up can damage both the driving and driven devices and can disrupt card power-up.

Stratix II devices do not have a current path from I/O pins, dedicated input pins, or dedicated clock pins to the V_{CCIO}, V_{CCINT}, or V_{CCPD} pins before or during power-up. A Stratix II device may be inserted into (or removed from) a powered-up system board without damaging or interfering with system-board operation. When hot-socketing, Stratix II devices may have a minimal effect on the signal integrity of the backplane.

You can power up or power down the V_{CCIO}, V_{CCINT}, and V_{CCPD} pins in any sequence. The power supply ramp rates can range from 100 µs to 100 ms. All V_{CC} supplies must power down within 100 ms of each other to prevent I/O pins from driving out. During hot socketing, the I/O pin capacitance is less than 15 pF and the clock pin capacitance is less than 20 pF. Stratix II devices meet the following hot socketing specification.

- The hot socketing DC specification is: $| I_{IOPIN} | < 300$ µA.
- The hot socketing AC specification is: $| I_{IOPIN} | < 8$ mA for 10 ns or less.

Document Revision History

Table 4–1 shows the revision history for this chapter.

Table 4–1. Document Revision History

Date and Document Version	Changes Made	Summary of Changes
May 2007, v3.2	Moved the Document Revision History section to the end of the chapter.	—
April 2006, v3.1	• Updated "Signal Pins Do Not Drive the VCCIO, VCCINT or VCCPD Power Supplies" section.	• Updated hot socketing AC specification.
May 2005, v3.0	• Updated "Signal Pins Do Not Drive the VCCIO, VCCINT or VCCPD Power Supplies" section. • Removed information on ESD protection.	—
January 2005, v2.1	Updated input rise and fall time.	—
January 2005, v2.0	Updated the "Hot Socketing Feature Implementation in Stratix II Devices", "ESD Protection", and "Power-On Reset Circuitry" sections.	—
July 2004, v1.1	• Updated all tables. • Added tables.	—
February 2004, v1.0	Added document to the Stratix II Device Handbook.	—

Table 5–27. 1.8-V HSTL Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.71	1.80	1.89	V
V_{REF}	Input reference voltage		0.85	0.90	0.95	V
V_{TT}	Termination voltage		0.85	0.90	0.95	V
V_{IH} (DC)	DC high-level input voltage		V_{REF} + 0.1			V
V_{IL} (DC)	DC low-level input voltage		–0.3		V_{REF} – 0.1	V
V_{IH} (AC)	AC high-level input voltage		V_{REF} + 0.2			V
V_{IL} (AC)	AC low-level input voltage				V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = 16 mA *(1)*	V_{CCIO} – 0.4			V
V_{OL}	Low-level output voltage	I_{OH} = –16 mA *(1)*			0.4	V

Note to Table 5–27:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–28. 1.8-V HSTL Class I & II Differential Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	I/O supply voltage		1.71	1.80	1.89	V
V_{DIF} (DC)	DC input differential voltage		0.2		V_{CCIO} + 0.6 V	V
V_{CM} (DC)	DC common mode input voltage		0.78		1.12	V
V_{DIF} (AC)	AC differential input voltage		0.4		V_{CCIO} + 0.6 V	V
V_{OX} (AC)	AC differential cross point voltage		0.68		0.90	V

Figure 5–6. Measurement Setup for t_{zx}

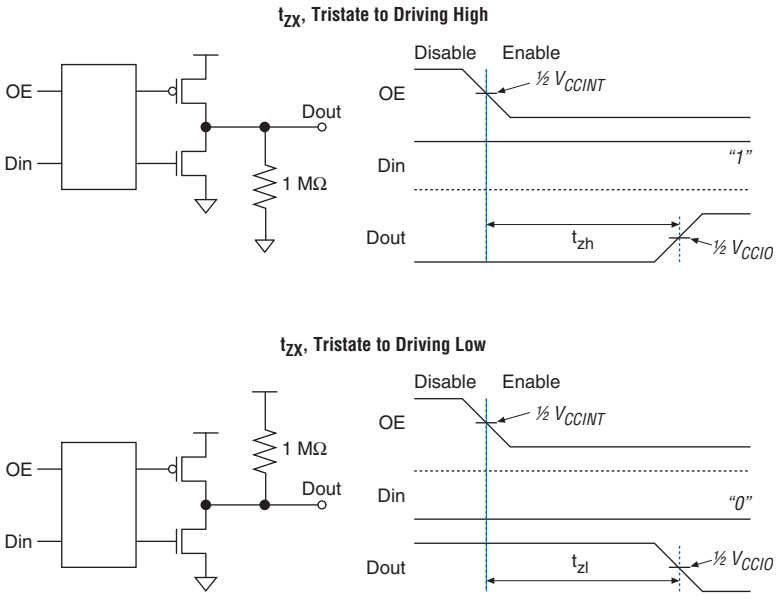


Table 5–35 specifies the input timing measurement setup.

Table 5–35. Timing Measurement Methodology for Input Pins (Part 1 of 2) *Notes (1)–(4)*

I/O Standard	Measurement Conditions			Measurement Point
	V_{CCIO} (V)	V_{REF} (V)	Edge Rate (ns)	V_{MEAS} (V)
LVTTL *(5)*	3.135		3.135	1.5675
LVCMOS *(5)*	3.135		3.135	1.5675
2.5 V *(5)*	2.375		2.375	1.1875
1.8 V *(5)*	1.710		1.710	0.855
1.5 V *(5)*	1.425		1.425	0.7125
PCI *(6)*	2.970		2.970	1.485
PCI-X *(6)*	2.970		2.970	1.485
SSTL-2 Class I	2.325	1.163	2.325	1.1625
SSTL-2 Class II	2.325	1.163	2.325	1.1625
SSTL-18 Class I	1.660	0.830	1.660	0.83
SSTL-18 Class II	1.660	0.830	1.660	0.83
1.8-V HSTL Class I	1.660	0.830	1.660	0.83

Table 5–40. M512 Block Internal Timing Microparameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
$t_{M512DATACO1}$	Clock-to-output delay when using output registers	298	478	298	501	284 298	548	298	640	ps
$t_{M512DATACO2}$	Clock-to-output delay without output registers	2,102	2,345	2,102	2,461	2,003 2,102	2,695	2,102	3,141	ps
$t_{M512CLKL}$	Minimum clock low time	1,315		1,380		1,512 1,512		1,762		ps
$t_{M512CLKH}$	Minimum clock high time	1,315		1,380		1,512 1,512		1,762		ps
$t_{M512CLR}$	Minimum clear pulse width	144		151		165 165		192		ps

Notes to Table 5–40:

(1) F_{MAX} of M512 block obtained using the Quartus II software does not necessarily equal to 1/TM512RC.
(2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
(3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
(4) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.
(5) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.

Table 5–41. M4K Block Internal Timing Microparameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
t_{M4KRC}	Synchronous read cycle time	1,462	2,240	1,462	2,351	1,393 1,462	2,575	1,462	3,000	ps
$t_{M4KWERESU}$	Write or read enable setup time before clock	22		23		25 25		29		ps
$t_{M4KWEREH}$	Write or read enable hold time after clock	203		213		233 233		272		ps
$t_{M4KBESU}$	Byte enable setup time before clock	22		23		25 25		29		ps
t_{M4KBEH}	Byte enable hold time after clock	203		213		233 233		272		ps

Table 5–71. Default Loading of Different I/O Standards for Stratix II (Part 2 of 2)

I/O Standard	Capacitive Load	Unit
SSTL-2 Class II	0	pF
SSTL-18 Class I	0	pF
SSTL-18 Class II	0	pF
1.5-V HSTL Class I	0	pF
1.5-V HSTL Class II	0	pF
1.8-V HSTL Class I	0	pF
1.8-V HSTL Class II	0	pF
1.2-V HSTL with OCT	0	pF
Differential SSTL-2 Class I	0	pF
Differential SSTL-2 Class II	0	pF
Differential SSTL-18 Class I	0	pF
Differential SSTL-18 Class II	0	pF
1.5-V Differential HSTL Class I	0	pF
1.5-V Differential HSTL Class II	0	pF
1.8-V Differential HSTL Class I	0	pF
1.8-V Differential HSTL Class II	0	pF
LVDS	0	pF
HyperTransport	0	pF
LVPECL	0	pF

Table 5–78. Maximum Output Toggle Rate on Stratix II Devices (Part 1 of 5) *Note (1)*

I/O Standard	Drive Strength	Column I/O Pins (MHz)			Row I/O Pins (MHz)			Clock Outputs (MHz)		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
3.3-V LVTTL	4 mA	270	225	210	270	225	210	270	225	210
	8 mA	435	355	325	435	355	325	435	355	325
	12 mA	580	475	420	580	475	420	580	475	420
	16 mA	720	594	520	-	-	-	720	594	520
	20 mA	875	700	610	-	-	-	875	700	610
	24 mA	1,030	794	670	-	-	-	1,030	794	670
3.3-V LVCMOS	4 mA	290	250	230	290	250	230	290	250	230
	8 mA	565	480	440	565	480	440	565	480	440
	12 mA	790	710	670	-	-	-	790	710	670
	16 mA	1,020	925	875	-	-	-	1,020	925	875
	20 mA	1,066	985	935	-	-	-	1,066	985	935
	24 mA	1,100	1,040	1,000	-	-	-	1,100	1,040	1,000
2.5-V LVTTL/LVCMOS	4 mA	230	194	180	230	194	180	230	194	180
	8 mA	430	380	380	430	380	380	430	380	380
	12 mA	630	575	550	630	575	550	630	575	550
	16 mA	930	845	820	-	-	-	930	845	820
1.8-V LVTTL/LVCMOS	2 mA	120	109	104	120	109	104	120	109	104
	4 mA	285	250	230	285	250	230	285	250	230
	6 mA	450	390	360	450	390	360	450	390	360
	8 mA	660	570	520	660	570	520	660	570	520
	10 mA	905	805	755	-	-	-	905	805	755
	12 mA	1,131	1,040	990	-	-	-	1,131	1,040	990
1.5-V LVTTL/LVCMOS	2 mA	244	200	180	244	200	180	244	200	180
	4 mA	470	370	325	470	370	325	470	370	325
	6 mA	550	430	375	-	-	-	550	430	375
	8 mA	625	495	420	-	-	-	625	495	420
SSTL-2 Class I	8 mA	400	300	300	-	-	-	400	300	300
	12 mA	400	400	350	400	350	350	400	400	350
SSTL-2 Class II	16 mA	350	350	300	350	350	300	350	350	300
	20 mA	400	350	350	-	-	-	400	350	350
	24 mA	400	400	350	-	-	-	400	400	350

Table 5–89. High-Speed I/O Specifications for -3 Speed Grade (Part 2 of 2) *Notes (1), (2)*

Symbol	Conditions			-3 Speed Grade			Unit
				Min	Typ	Max	
f_{HSDR} (data rate)	J = 4 to 10 (LVDS, HyperTransport technology)			150		1,040	Mbps
	J = 2 (LVDS, HyperTransport technology)			*(4)*		760	Mbps
	J = 1 (LVDS only)			*(4)*		500	Mbps
$f_{HSDRDPA}$ (DPA data rate)	J = 4 to 10 (LVDS, HyperTransport technology)			150		1,040	Mbps
TCCS	All differential standards			-		200	ps
SW	All differential standards			330		-	ps
Output jitter						190	ps
Output t_{RISE}	All differential I/O standards					160	ps
Output t_{FALL}	All differential I/O standards					180	ps
t_{DUTY}				45	50	55	%
DPA run length						6,400	UI
DPA jitter tolerance	Data channel peak-to-peak jitter			0.44			UI
DPA lock time	**Standard**	**Training Pattern**	**Transition Density**				Number of repetitions
	SPI-4	0000000000 1111111111	10%	256			
	Parallel Rapid I/O	00001111	25%	256			
		10010000	50%	256			
	Miscellaneous	10101010	100%	256			
		01010101		256			

Notes to Table 5–89:

(1) When J = 4 to 10, the SERDES block is used.

(2) When J = 1 or 2, the SERDES block is bypassed.

(3) The input clock frequency and the W factor must satisfy the following fast PLL VCO specification: 150 ≤ input clock frequency × W ≤ 1,040.

(4) The minimum specification is dependent on the clock source (fast PLL, enhanced PLL, clock pin, and so on) and the clock routing resource (global, regional, or local) utilized. The I/O differential buffer and input register do not have a minimum toggle rate.

Table 5–100. DQS Phase Offset Delay Per Stage Notes (1), (2), (3)			
Speed Grade	**Min**	**Max**	**Unit**
-3	9	14	ps
-4	9	14	ps
-5	9	15	ps

Notes to Table 5–100:
(1) The delay settings are linear.
(2) The valid settings for phase offset are -64 to +63 for frequency mode 0 and -32 to +31 for frequency modes 1, 2, and 3.
(3) The typical value equals the average of the minimum and maximum values.

Table 5–101. DDIO Outputs Half-Period Jitter Notes (1), (2)			
Name	**Description**	**Max**	**Unit**
$t_{OUTHALFJITTER}$	Half-period jitter (PLL driving DDIO outputs)	200	ps

Notes to Table 5–101:
(1) The worst-case half period is equal to the ideal half period subtracted by the DCD and half-period jitter values.
(2) The half-period jitter was characterized using a PLL driving DDIO outputs.

JTAG Timing Specifications

Figure 5–10 shows the timing requirements for the JTAG signals.

Figure 5–10. Stratix II JTAG Waveforms

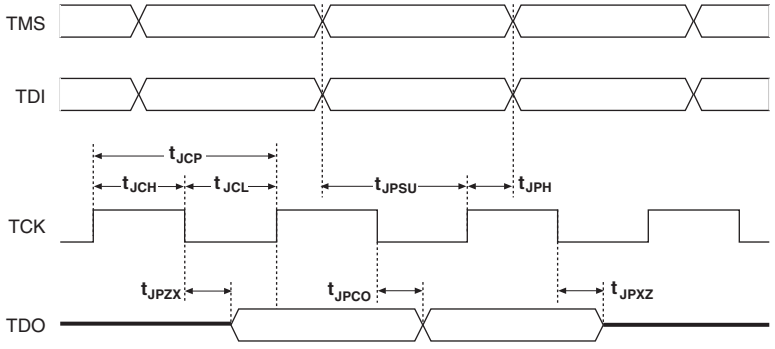


Table 5–103. Document Revision History (Part 3 of 3)

Date and Document Version	Changes Made	Summary of Changes
January 2005, v2.0	• Updated the "Power Consumption" section. • Added the "High-Speed I/O Specifications" and "On-Chip Termination Specifications" sections. • Removed the ESD Protection Specifications section. • Updated Tables 5–3 through 5–13, 5–16 through 5–18, 5–21, 5–35, 5–39, and 5–40. • Updated tables in "Timing Model" section. • Added Tables 5–30 and 5–31.	—
October 2004, v1.2	• Updated Table 5–3. • Updated introduction text in the "PLL Timing Specifications" section.	—
July 2004, v1.1	• Re-organized chapter. • Added typical values and C_{OUTFB} to Table 5–32. • Added undershoot specification to Note (4) for Tables 5–1 through 5–9. • Added Note (1) to Tables 5–5 and 5–6. • Added V_{ID} and V_{ICM} to Table 5–10. • Added "I/O Timing Measurement Methodology" section. • Added Table 5–72. • Updated Tables 5–1 through 5–2 and Tables 5–24 through 5–29.	—
February 2004, v1.0	Added document to the Stratix II Device Handbook.	—